

# AN3215K, AN3215S

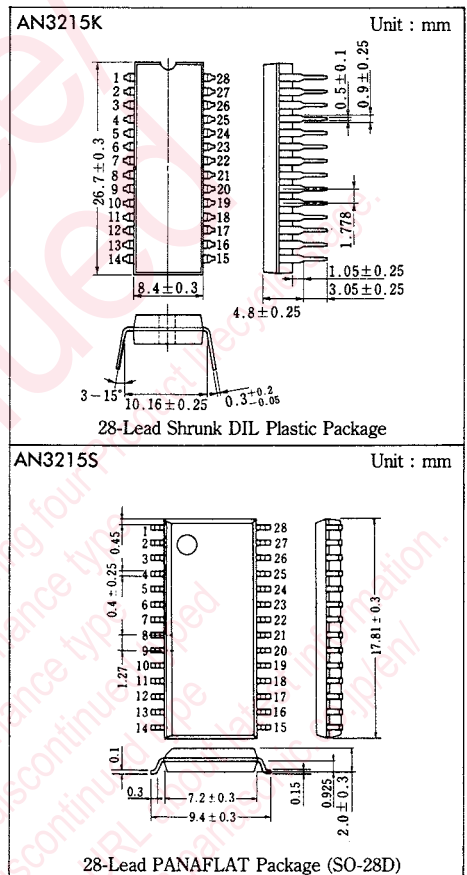
## VTR Recording Video Signal Processing Circuits

### Outline

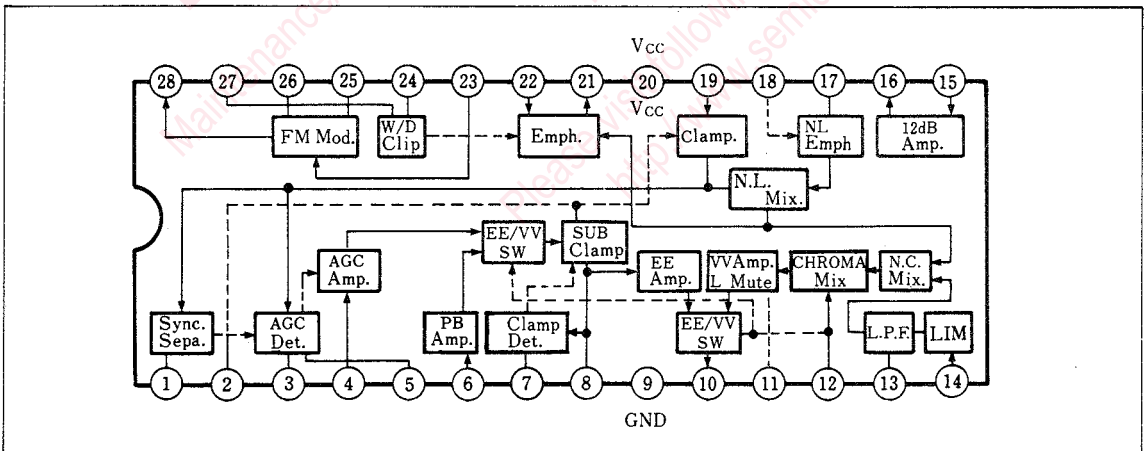
The AN 3215K and the AN3215S are integrated circuits designed for VTR recording video signal processing circuits.

### Features

- Dynamic emphasis characteristics (in accordance with VHS standard): 7.0dB (at  $f=1\text{MHz}$ , input level =  $-20\text{dB}$ )
- Built-in carrier interleaving circuit
- Built-in low pass filter. (Sync-separation circuit)
- Supply voltage :  $V_{cc}=5\text{V}$



### Block Diagram



■ Absolute Maximum Ratings (Ta=25°C)

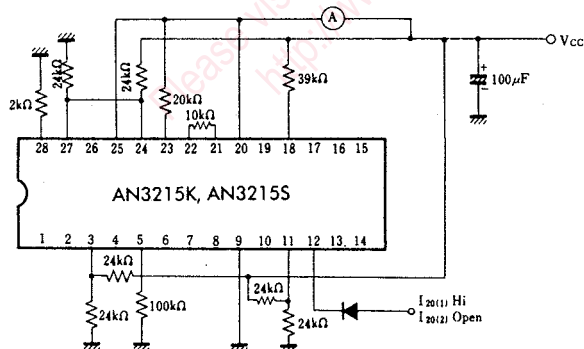
Item	Symbol	Rating	Unit
Supply Voltage	V <sub>CC</sub>	6.0	V
Power Dissipation(Ta=70°C)	P <sub>D</sub>	250	mW
Operating Ambient Temperature	T <sub>opr</sub>	-20~+70	°C
Storage Temperature	T <sub>stg</sub>	-55~+150	°C

■ Electrical Characteristics (V<sub>CC</sub>=5V, Ta=25°C)

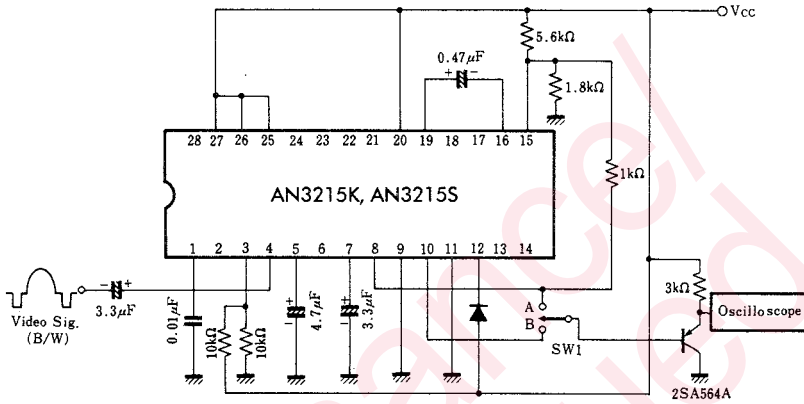
Item	Symbol	Test Circuit	Condition	min.	typ.	max.	Unit
Circuit Current(1)	I <sub>20(1)</sub>	1	Pin ⑫ Hi (Rec)	14.5		35.5	mA
Circuit Current(2)	I <sub>20(2)</sub>	1	Pin ⑫ Open (PB)	14.5		35.5	mA
AGC Output Amplification	v <sub>8</sub>	2	Pin ⑫ Hi	0.4		0.8	V <sub>P-P</sub>
AGC Control Sensitivity	β <sub>8</sub>	2	Pin ⑫ Hi			1.5	dB
PB Amp. Gain	G <sub>6-8</sub>	3	Pin ⑫ Open	6.8		9.9	dB
12dB Amp. Gain	G <sub>15-16</sub>	3		10.4		13.4	dB
FM Oscillation Frequency	f <sub>o</sub>	4	Pin ⑫ Hi, Co=39pF, Ro=12kΩ	2.9		3.9	MHz
FM Output 2nd High Frequency	2f <sub>o</sub>	4	Pin ⑫ Hi, Co=39pF, Ro=12kΩ			-33	dB
FM Oscillation Output Amplification	v <sub>28</sub>	4	Pin ⑫ Hi, Co=39pF, Ro=12kΩ	0.65		1.35	V <sub>P-P</sub>
Frequency Control Sensitivity FM Oscillation	β <sub>28</sub>	4	Pin ⑫ Hi, Co=39pF, Ro=8.2~15kΩ	11.4		14.5	kHz/μA
Sync. Spea. Input Sensitivity	S <sub>19</sub>	5	Video Input V/S=5/2	0.45			V <sub>P-P</sub>
Sync. Spea. Output Amplification	v <sub>2</sub>	5	Video Input V/S=5/2	4.3			V <sub>P-P</sub>
NL Limiter Gain	v <sub>17-21</sub>	6	Pin ⑫ Hi	30		52	mV <sub>P-P</sub>
NL Limiter Output Amplification(1)	v <sub>21(1)</sub>	6	Pin ⑫ Hi	48		72	mV <sub>P-P</sub>
NL Limiter Output Amplification(2)	v <sub>21(2)</sub>	6	Pin ⑫ Hi, Pin ⑬ Lo	16		37	mV <sub>P-P</sub>
NC Limiter Gain	v <sub>14-10</sub>	7	Pin ⑫ Open	30		70	mV <sub>P-P</sub>
NC Limiter Output Amplification	v <sub>10</sub>	7	Pin ⑫ Open	65		125	mV <sub>P-P</sub>
EE Amp. Gain	G <sub>8-10</sub>	2	Pin ⑫ Hi	9.7		11.6	dB
VV Amp. Gain	v <sub>19-10</sub>	3	Pin ⑫ Open	1.65		2.15	V <sub>P-P</sub>
Chroma Amp. Gain	G <sub>12-10</sub>	7		5.3		8.8	dB
EE/VV Crosstalk	CT <sub>19-10</sub>	8	E≧4.0V			-40	dB
Mute Crosstalk	CT' <sub>19-10</sub>	8	Pin ⑫ Lo, Pin ⑪ Hi			-40	dB
EE/VV Changeover Sensitivity	S <sub>12</sub>	8		4			V
FM Oscillation Carrier Interleave	Δf <sub>o</sub> *	9	Pin ⑫ Hi	5.9		9.9	kHz
V offset	Δv <sub>19-10</sub> *	3	Pin ⑫ Lo	-30		110	mV

Note : Operating Supply Voltage Range V<sub>CC</sub>=4.5~5.5V \* It is design value but not a guaranteed value.

Test Circuit 1 (I<sub>20(1)</sub>, I<sub>20(2)</sub>)

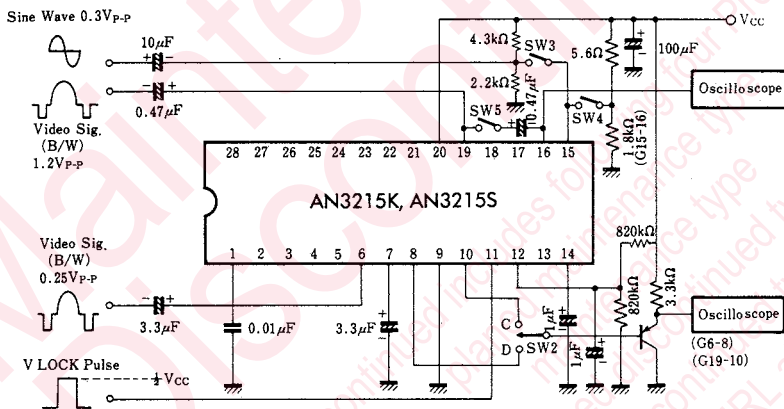


Test Circuit 2 ( $v_B, \Delta v_B, G_{8-10}$ )



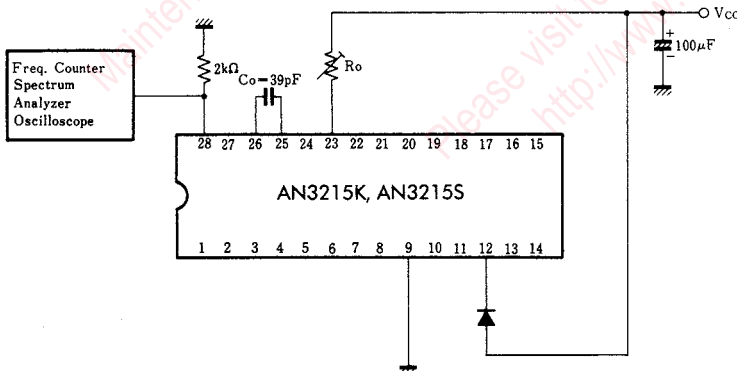
- $U_B$
- IN: 1.0V<sub>P-P</sub>
- $\Delta U_B$
- Output amplification change between IN: 0.5V<sub>P-P</sub> to 2.0V<sub>P-P</sub>
- $G_{8-10}$
- IN: 1.0V<sub>P-P</sub>
- Ratio of output when SW1 is B to output when SW1 is A

Test Circuit 3 ( $G_{6-8}, G_{15-16}, v_{19-10}, \Delta v_{19-10}$ )



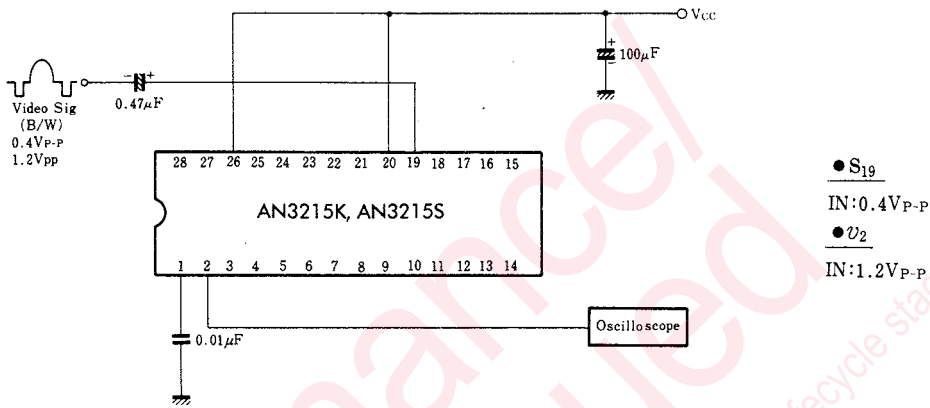
- $G_{6-8}$
- IN: pin ⑥ 0.25V<sub>P-P</sub>
- SW2: D
- $G_{15-16}$
- IN: pin ⑮ 0.3V<sub>P-P</sub>
- SW3: ON
- SW4: OFF
- SW5: OFF
- $U_{19-10}$
- IN: pin ⑱ 1.2V<sub>P-P</sub>
- SW2: C
- SW5: OFF
- $\Delta U_{19-10}$
- IN: pin ⑱ 1.2V<sub>P-P</sub>
- SW2: C
- SW5: OFF

Test Circuit 4 ( $f_0, 2f_0, v_{28}, \beta_{28}$ )

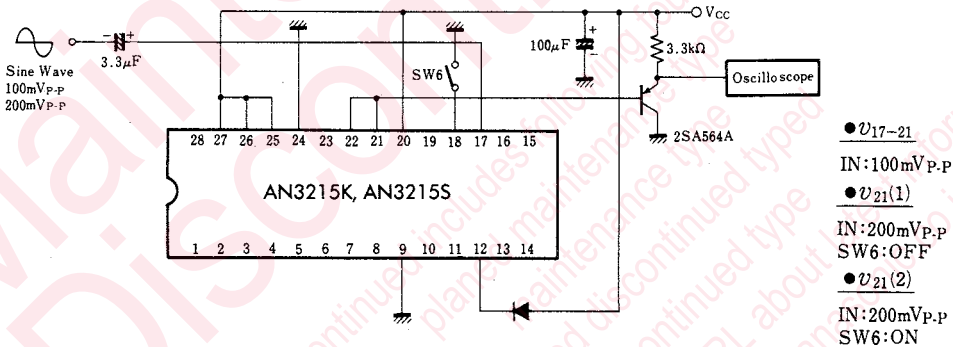


- $f_0, 2f_0, v_{28}$
- $R_o = 12k\Omega$
- $\beta_{28}$
- Measure a change of oscillation frequency when  $R_o = 8.2k\Omega \sim 15K\Omega$

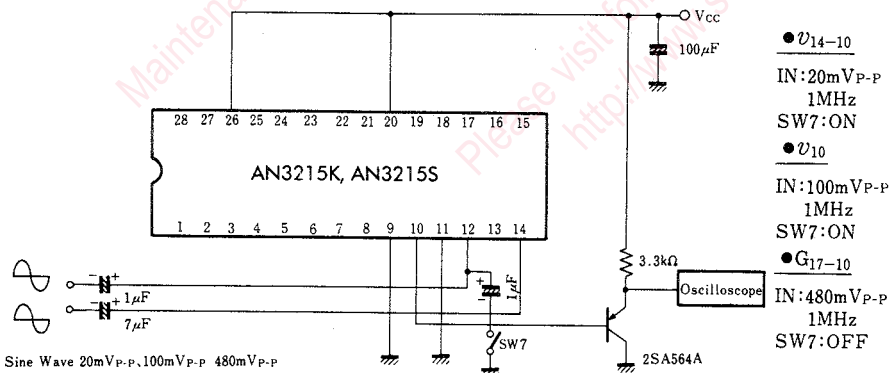
Test Circuit 5 ( $S_{19}$ ,  $v_2$ )



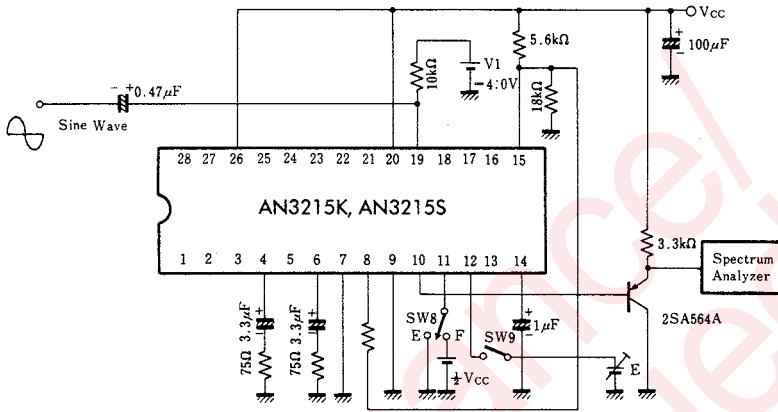
Test Circuit 6 ( $v_{17-21}$ ,  $v_{21(1)}$ ,  $v_{21(2)}$ )



Test Circuit 7 ( $v_{14-10}$ ,  $v_{10}$ ,  $G_{12-10}$ )

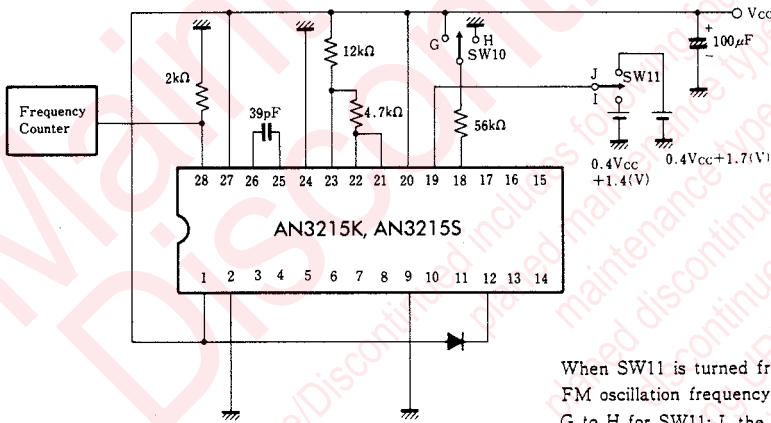


Test Circuit 8 (CT<sub>19-10</sub>, CT'<sub>19-10</sub>, S<sub>12</sub>)



- CT<sub>19-10</sub>  
IN: 0.25V<sub>P-P</sub> 1MHz  
Measure the attenuation when SW9 is turned from OFF to ON.
- CT'<sub>19-10</sub>  
IN: 0.25V<sub>P-P</sub> 1MHz  
Measure the attenuation when SW8 is turned from E to F.
- S<sub>12</sub>  
IN: 0.25V<sub>P-P</sub> 1MHz  
Pin 10 voltage when the output signal for SW9:ON becomes -40dB or less.

Test Circuit 9 (Δf<sub>0</sub>)



When SW11 is turned from I to J for SW10:G, the difference of FM oscillation frequency is  $|\Delta f_1|$ . When SW10 is turned from G to H for SW11: I, the difference of FM oscillation frequency is  $|\Delta f_2|$ . At this time, FM carrier interleave ratio  $\Delta f_0$  is given by the following equation.

$$\Delta f_0 = \frac{|\Delta f_2|}{|\Delta f_1|} 250 \text{ (kHz)}$$

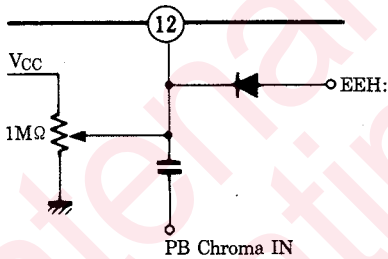


Notes for Use

In the electrical characteristics table of dummy V offset  $V_{19-10}$ ,  $-30$  to  $110$  (mV) is listed as reference value. If exceeded beyond this max. value, V synchronization for special regeneration is not made, resulting in being under minimum of the value. In such cases, a skew may be generated on the top of the display screen.

In these specifications for product, the reference value, from the view point of the set quality purpose, is listed just for reference for design. However, it is very unstable if used for ICs. So please be sure to take some measures such as external adjustment, etc. for this point when you use.

(Example of external adjustment circuit)



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